

<b>Notice of References Cited</b>			Application/Control No.	Applicant(s)/Patent Under Reexamination	
			10/694,175	UEDA, SATOSHI	
Examiner			Art Unit	Jacky X. Zheng	
			2625	Page 1 of 1	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,036,361 A	07-1991	Filion et al.	399/81
*	B	US-5,809,371 A	09-1998	Inui et al.	399/81
*	C	US-5,960,234 A	09-1999	Shibaki et al.	399/75
*	D	US-6,124,943 A	09-2000	Mitani, Keisuke	358/1.17
*	E	US-6,186,682 B1	02-2001	Ishiyama, Masahiro	400/76
*	F	US-2002/0135799 A1	09-2002	Simpson et al.	358/1.15
*	G	US-2003/0059223 A1	03-2003	Ushio et al.	399/75
*	H	US-6,636,324 B2	10-2003	Yamamoto, Masahito	358/1.13
*	I	US-6,652,819 B2	11-2003	Shiroto et al.	423/62
*	J	US-2004/0012797 A1	01-2004	Letellier, Nolan Wayne	358/1.9
*	K	US-6,709,176 B2	03-2004	Gotoh et al.	400/61
*	L	US-6,728,499 B2	04-2004	Ushio et al.	399/75
*	M	US-7,046,383 B1	05-2006	Ueda et al.	358/1.15

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000153659 A	06-2000	Japan	HARA et al.	B41J 29/42
	O	JP 2001018497 A	01-2001	Japan	TANAKA, CHIHARU	B41J 29/42
	P	JP 2001042451 A	02-2001	Japan	FUKUSHIMA et al.	G03B 27/46
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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